Evaluation of Life Testing Schemes

Paul Britton, NASA Kelby Starchman, Bastion

paul.t.britton@nasa.gov kelby.l.starchman@nasa.gov

Contents

- Background
- Weibull Distribution Overview
- Problem Statement
- Default Approach
- A More Pragmatic and Useful Approach
- Measuring Reliability from Data
- Visualization of Qualification Effectiveness
- Revised Problem Statement
- Summary

Background

- We will explore the age-old question: What reliability can we infer from a qualification life test with zero failures? Moreover, we will offer an alternate and more pragmatic way to approach this problem.
- Notional Situation:
	- If we test 4 Units to 2x Lives without failure, can we infer the same reliability as if we tested 1 Unit to 4x Lives?
- Ground rules:
	- The life distribution is Weibull
	- The failure mode of interest is wear-out
	- The reliability requirement is 0.99
	- The Notional Program has high tolerance for risk

Weibull Distribution Overview
\n
$$
f(x) = \frac{\beta}{\eta} \left(\frac{x}{\eta}\right)^{\beta-1} e^{-(xT\eta)^{\beta}}
$$
\n
$$
F(x) \stackrel{\text{def}}{=} \mathfrak{D} f y dt = 1 - e^{-(xT\eta)^{\beta}}
$$

 $F(x)$

Example Weibull plots for beta = 4 , eta = 3

 $f(x)$ +

- beta represents the acceleration of failure rate
- eta represents characteristic life independent of beta

Failure Space

 $\mathbf 0$

Note1: $F(\eta) \cong 0.63$ and $S(\eta) \cong 0.37$

Note2: For $\beta > 1$, $h(x)$ increases over time

 $S(x) = 1 - F(x)$

 $h(x) = f(x) / S(x)$

Problem Statement

•Given that design life qualification is successful, what reliability can we infer?

• Misconception: Design life qualification tests informs reliability

Default Approach

- This requires finding the optimal Weibull fit using the data from the qualification test
- Mathematically, this optimization problem has unbounded solutions, at best, if not undefined
- However, if we *fix the shape parameter beta*, then a solution for eta can be found; and reliability can be calculated at a given confidence level
- **The issue** with this approach is that it makes a weakly supported yet a very specific defining assumption to obtain a solution

A More Pragmatic and Useful Approach

- Qualification success criteria is pass/fail in nature
	- To minimize false positive and false negative test errors we follow the structured procedure below
- Use engineering judgment and a bootstrapping strategy to make data driven steps towards useful conclusions
	- Step 0) Solicit Program reliability thresholds and risk posture
	- Step 1) Collect development and failure mode data
	- Step 2) Perform Weibull Analysis on anticipated Qualification test results
	- Step 3) Construct contour overlays based on Weibull Analysis
	- Step 4) Evaluate Qualification Test Effectiveness against objective measures
	- Step 5) Iterate on Qualification success criteria, if needed

Measuring Reliability from Data

- Survival curve fits, based on three sets of hypothetical 4-Unit Qualification Tests using Median Rank Regression
- For these sets, the ranges **beta = [2, 6] and eta = [1.5, 4.5]** establish a **focusregion** of anticipated Weibull parameters

Visualization of Qualification Effectiveness

- **1x Mission Reliability (S(1))** overlaid onto **Probability of Successful Qualification (S(x)^n)** reveals the landscape of false positives and false negatives for different qualification test schemes
- The **focus region (beta = [2, 6] and eta = [1.5, 4.5])** , derived from data that is likely to be representative of anticipated designs

Revised Problem Statement

• Optimize Cost, Schedule and Reliability Qualification Test Effectiveness

• **Solution:** Given a reliability threshold and risk posture for false negatives and false positive risk, contour overlays can aid in objectively measure the effectiveness of a qualification test scheme

Summary

Backup

Uncertainty in Reliability Estimation

- Comparison of notional Median Rank Regression **survival curve fits** with **90% confidence intervals** and **(Failure Time, Median Rank) points**
- Estimated uncertainty is sensitive to the sample size, goodness of fit, and variability in sampled values

66660 660 666.0 $\ddot{\bullet}$ \sim \overline{z} \circ \mathfrak{g} $rac{a}{a}$ 4 ∞ $=0.97$ \sim $-0.5-- \overline{}$ $\overline{2}$ $\overline{7}$ $\mathbf{1}$ $\mathbf{3}$ $\overline{5}$ $\,$ 6 $\overline{4}$ beta

 $10u-1x$ 66660 666.0 0.9 6.96 $\overline{ }$ \circ \mathfrak{g} $rac{a}{6}$ 4 ∞ \sim $\overline{}$ \overline{a} $\mathbf{3}$ $\sqrt{5}$ $\,$ 6 7 $\mathbf{1}$ beta

 $20u-1x$